

<b>Notice of References Cited</b>	Application/Control No. 10/771,669		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner KENT WANG		Art Unit 2622	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,946,817	09-2005	Fischer et al.	320/132
*	B	US-6,128,040	10-2000	Shinbori et al.	348/372
*	C	US-6,151,652	11-2000	Kondo et al.	713/300
*	D	US-6,184,652	02-2001	Yang, Wen-Chin	320/110
*	E	US-2003/0148663	08-2003	Hsin, Liao Sheng	439/638
*	F	US-2004/0203275	10-2004	Jeansonne et al.	439/378
*	G	US-6,424,123	07-2002	Odaohhara et al.	320/134
*	H	US-6,798,173	09-2004	Hsu, Ying-Hao	320/134
*	I	US-5,870,615	02-1999	Bar-On et al.	713/310
*	J	US-5,606,704	02-1997	Pierce et al.	713/322
*	K	US-5,561,772	10-1996	Dornier et al.	710/300
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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